

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under  
Reexamination  
KEENER, MARK BRADFORD

Examiner

Tan Dean D. Nguyen

Art Unit

3689

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	D	US-			
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	M	US-			

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**NON-PATENT DOCUMENTS**

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